

SLRS027M - DECEMBER 1976-REVISED FEBRUARY 2013

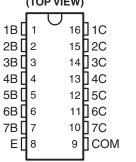
# HIGH-VOLTAGE, HIGH-CURRENT DARLINGTON TRANSISTOR ARRAYS

Check for Samples: ULN2002A, ULN2003A, ULN2003AI, ULN2004A, ULQ2003A, ULQ2004A

## **FEATURES**

- 500-mA-Rated Collector Current (Single Output)
- High-Voltage Outputs: 50 V
- Output Clamp Diodes
- Inputs Compatible With Various Types of Logic
- Relay-Driver Applications

ULN2002A ... N PACKAGE
ULN2003A ... D, N, NS, OR PW PACKAGE
ULN2004A ... D, N, OR NS PACKAGE
ULQ2003A, ULQ2004A ... D OR N PACKAGE
(TOP VIEW)



#### **DESCRIPTION**

The ULN2002A, ULN2003A, ULN2003AI, ULN2004A, ULQ2003A, and ULQ2004A are high-voltage high-current Darlington transistor arrays. Each consists of seven npn Darlington pairs that feature high-voltage outputs with common-cathode clamp diodes for switching inductive loads. The collector-current rating of a single Darlington pair is 500 mA. The Darlington pairs can be paralleled for higher current capability. Applications include relay drivers, hammer drivers, lamp drivers, display drivers (LED and gas discharge), line drivers, and logic buffers. For 100-V (otherwise interchangeable) versions of the ULN2003A and ULN2004A, see the SN75468 and SN75469, respectively.

The ULN2002A is designed specifically for use with 14-V to 25-V PMOS devices. Each input of this device has a Zener diode and resistor in series to control the input current to a safe limit. The ULN2003A and ULQ2003A have a 2.7-k $\Omega$  series base resistor for each Darlington pair for operation directly with TTL or 5-V CMOS devices. The ULN2004A and ULQ2004A have a 10.5-k $\Omega$  series base resistor to allow operation directly from CMOS devices that use supply voltages of 6 V to 15 V. The required input current of the ULN/ULQ2004A is below that of the ULN/ULQ2003A, and the required voltage is less than that required by the ULN2002A.



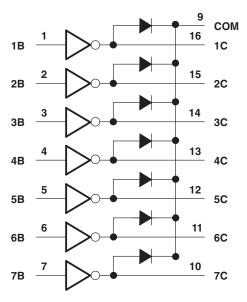


# ORDERING INFORMATION<sup>(1)</sup>

T <sub>A</sub>	P	ACKAGE <sup>(2)</sup>	ORDERABLE PART NUMBER	TOP-SIDE MARKING
			ULN2002AN	ULN2002AN
	PDIP – N	Tube of 25	ULN2003AN	ULN2003AN
			ULN2004AN	ULN2004AN
		Tube of 40	ULN2003AD	
		Reel of 2500	ULN2003ADR	ULN2003A
20°C to 70°C	SOIC - D	Reel of 2500	ULN2003ADRG3	
–20°C to 70°C		Tube of 40	ULN2004AD	LII N2004A
		Reel of 2500	ULN2004ADRG3	ULN2004A
	000 110	Dool of 2000	ULN2003ANSR	ULN2003A
	SOP – NS	Reel of 2000	ULN2004ANSR	ULN2004A
	TSSOP – PW	Tube of 90	ULN2003APW	LINIOOOOA
	1550P – PW	Reel of 2000	ULN2003APWR	UN2003A
	DDID 11	Tub a at 05	ULQ2003AN	ULQ2003A
	PDIP – N	Tube of 25	ULQ2004AN	ULQ2004AN
–40°C to 85°C		Tube of 40	ULQ2003AD	ULQ2003A
-40°C 10 85°C	colo D	Reel of 2500	ULQ2003ADR	ULQ2003A
	SOIC – D	Tube of 40	ULQ2004AD	LII 00004A
		Reel of 2500	ULQ2004ADR	ULQ2004A
	SOP - NS	Reel of 2000	ULN2003AINSR	ULN2003AI
	PDIP – N	Tube of 425	ULN2003AIN	ULN2003AIN
–40°C to 105°C	2010 D	Tube of 40	ULN2003AID	LII N2002 A I
	SOIC – D	Reel of 2500	ULN2003AIDR	ULN2003AI
	TSSOP - PW	Reel of 2500	ULN2003AIPWR	UN2003AI

<sup>(1)</sup> For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.

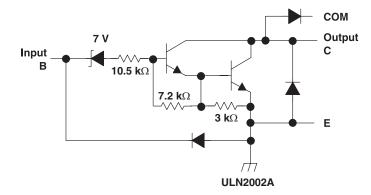
## **LOGIC DIAGRAM**

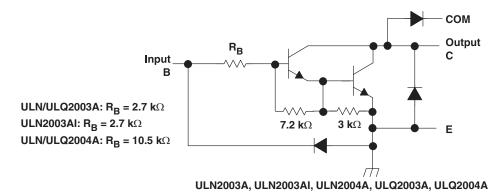


<sup>(2)</sup> Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.



# **SCHEMATICS (EACH DARLINGTON PAIR)**





All resistor values shown are nominal.

The collector-emitter diode is a parasitic structure and should not be used to conduct current. If the collector(s) go below ground an external Schottky diode should be added to clamp negative undershoots.



# **ABSOLUTE MAXIMUM RATINGS(1)**

at 25°C free-air temperature (unless otherwise noted)

			MIN	MAX	UNIT	
V <sub>CC</sub>	Collector-emitter voltage			50	V	
	Clamp diode reverse voltage <sup>(2)</sup>			50	V	
VI	Input voltage <sup>(2)</sup>			30	V	
	Peak collector current	See Figure 14 and Figure 15		500	mA	
I <sub>OK</sub>	Output clamp current			500	mA	
	Total emitter-terminal current			-2.5	Α	
		ULN200xA	-20	70		
_	Occupation for a sin to see a section of the sectio	ULN200xAI	-40	105	°C	
$T_A$	Operating free-air temperature range	ULQ200xA	-40	85	30	
		ULQ200xAT	-40	105		
		D package		73		
^	Decline to the consoline or address (3) (4)	N package		67		
$\theta_{JA}$	Package thermal impedance (3) (4)	NS package		64	0000	
		PW package		108	°C/W	
^	Decline at the consoline and consol(5) (6)	D package		36		
$\theta_{JC}$	Package thermal impedance (5) (6)	N package		54		
TJ	Operating virtual junction temperature			150	°C	
	Lead temperature for 1.6 mm (1/16 inch) from case for 10	seconds		260	°C	
T <sub>stg</sub>	Storage temperature range		-65	150	°C	

- (1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) All voltage values are with respect to the emitter/substrate terminal E, unless otherwise noted.
- (3) Maximum power dissipation is a function of  $T_J(max)$ ,  $\theta_{JA}$ , and  $T_A$ . The maximum allowable power dissipation at any allowable ambient temperature is  $P_D = (T_J(max) T_A)/\theta_{JA}$ . Operating at the absolute maximum  $T_J$  of 150°C can affect reliability.
- (4) The package thermal impedance is calculated in accordance with JESD 51-7.
- (5) Maximum power dissipation is a function of T<sub>J</sub>(max), θ<sub>JC</sub>, and T<sub>A</sub>. The maximum allowable power dissipation at any allowable ambient temperature is P<sub>D</sub> = (T<sub>J</sub>(max) T<sub>A</sub>)/θ<sub>JC</sub>. Operating at the absolute maximum T<sub>J</sub> of 150°C can affect reliability.
- (6) The package thermal impedance is calculated in accordance with MIL-STD-883.

#### **ELECTRICAL CHARACTERISTICS**

 $T_A = 25^{\circ}C$ 

	DADAMETER	TEST	TEST OF	NDITIONS	UL	UNIT		
	PARAMETER	FIGURE	IESI CC	TEST CONDITIONS		TYP	MAX	UNII
V <sub>I(on)</sub>	On-state input voltage	Figure 6	V <sub>CE</sub> = 2 V,	I <sub>C</sub> = 300 mA			13	V
			$I_{I} = 250 \mu A$ ,	$I_C = 100 \text{ mA}$		0.9	1.1	
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	Figure 4	$I_I = 350 \ \mu A$	$I_C = 200 \text{ mA}$		1	1.3	V
			$I_{I} = 500 \ \mu A$	$I_C = 350 \text{ mA}$		1.2	1.6	
$V_{F}$	Clamp forward voltage	Figure 7	I <sub>F</sub> = 350 mA			1.7	2	V
		Figure 1	$V_{CE} = 50 \text{ V},$	I <sub>1</sub> = 0			50	
I <sub>CEX</sub>	Collector cutoff current	Figure 2	$V_{CE} = 50 \text{ V},$	$I_1 = 0$			100	μΑ
			gure 2 $T_A = 70^{\circ}C$	$V_I = 6 V$			500	
I <sub>I(off)</sub>	Off-state input current	Figure 2	$V_{CE} = 50 \text{ V},$	$I_{C} = 500 \ \mu A$	50	65		μΑ
I	Input current	Figure 3	V <sub>I</sub> = 17 V			0.82	1.25	mA
		Figure 6	V 50.V	T <sub>A</sub> = 70°C			100	
I <sub>R</sub>	Clamp reverse current	Figure 6	V <sub>R</sub> = 50 V				50	μA
C <sub>i</sub>	Input capacitance		$V_I = 0$ ,	f = 1 MHz			25	pF





## **ELECTRICAL CHARACTERISTICS**

 $T_A = 25^{\circ}C$ 

www.ti.com

	DADAMETED	TEST	TEST OF	NIDITIONS	UL	N2003	4	UL	N2004	A	UNIT
	PARAMETER	FIGURE	IESI CC	ONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNII
				I <sub>C</sub> = 125 mA						5	
				I <sub>C</sub> = 200 mA			2.4			6	
	0	F:	.,	I <sub>C</sub> = 250 mA			2.7				.,
$V_{I(on)}$	On-state input voltage	Figure 6	$V_{CE} = 2 V$	I <sub>C</sub> = 275 mA						7	V
				I <sub>C</sub> = 300 mA			3				
				I <sub>C</sub> = 350 mA						8	
			$I_I = 250 \ \mu A$ ,	I <sub>C</sub> = 100 mA		0.9	1.1		0.9	1.1	
$V_{CE(sat)}$	Collector-emitter saturation voltage	Figure 5	$I_1 = 350 \ \mu A$	I <sub>C</sub> = 200 mA		1	1.3		1	1.3	V
	Saturation voltage		$I_I = 500 \ \mu A$	I <sub>C</sub> = 350 mA		1.2	1.6		1.2	1.6	
		Figure 1	V <sub>CE</sub> = 50 V,	$I_1 = 0$			50			50	
$I_{CEX}$	Collector cutoff current	Figure 2	$V_{CE} = 50 \text{ V},$	$I_1 = 0$			100			100	μΑ
		Figure 2	$T_A = 70^{\circ}C$	V <sub>I</sub> = 6 V						500	
V <sub>F</sub>	Clamp forward voltage	Figure 8	I <sub>F</sub> = 350 mA			1.7	2		1.7	2	V
I <sub>I(off)</sub>	Off-state input current	Figure 3	V <sub>CE</sub> = 50 V, T <sub>A</sub> = 70°C,	I <sub>C</sub> = 500 μA	50	65		50	65		μΑ
			V <sub>I</sub> = 3.85 V			0.93	1.35				
l <sub>l</sub>	Input current	Figure 4	V <sub>I</sub> = 5 V						0.35	0.5	mA
			V <sub>I</sub> = 12 V						1	1.45	
	01	F:	., 50.1/				50			50	
$I_R$	Clamp reverse current	Figure 7	$V_R = 50 \text{ V}$	T <sub>A</sub> = 70°C			100			100	μA
Ci	Input capacitance		$V_1 = 0$ ,	f = 1 MHz		15	25		15	25	pF

## **ELECTRICAL CHARACTERISTICS**

 $T_{\Lambda} = 25^{\circ}C$ 

	DADAMETED	TEST FIGURE	TEST		UL	N2003A	.I	LINUT
	PARAMETER	TEST FIGURE	CONDITIONS		MIN	TYP	MAX	UNIT
				I <sub>C</sub> = 200 mA			2.4	
V <sub>I(on)</sub>	On-state input voltage	Figure 6	V <sub>CE</sub> = 2 V	I <sub>C</sub> = 250 mA			2.7	V
				I <sub>C</sub> = 300 mA			3	
			$I_I = 250 \mu A$ ,	I <sub>C</sub> = 100 mA		0.9	1.1	
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	Figure 5	$I_I = 350 \mu A$ ,	I <sub>C</sub> = 200 mA		1	1.3	V
			$I_I = 500 \mu A$ ,	I <sub>C</sub> = 350 mA		1.2	1.6	
I <sub>CEX</sub>	Collector cutoff current	Figure 1	V <sub>CE</sub> = 50 V,	$I_1 = 0$			50	μA
V <sub>F</sub>	Clamp forward voltage	Figure 8	I <sub>F</sub> = 350 mA			1.7	2	V
I <sub>I(off)</sub>	Off-state input current	Figure 3	V <sub>CE</sub> = 50 V,	I <sub>C</sub> = 500 μA	50	65		μΑ
I	Input current	Figure 4	V <sub>I</sub> = 3.85 V			0.93	1.35	mA
I <sub>R</sub>	Clamp reverse current	Figure 7	V <sub>R</sub> = 50 V				50	μΑ
Ci	Input capacitance		$V_1 = 0$ ,	f = 1 MHz		15	25	pF



#### **ELECTRICAL CHARACTERISTICS**

 $T_A = -40$ °C to 105°C

	PARAMETER	TEST FIGURE	TEST C	TEST CONDITIONS			.I	UNIT
	PARAMETER	1EST FIGURE	IESI C	TEST CONDITIONS		TYP	MAX	UNIT
				$I_C = 200 \text{ mA}$			2.7	
V <sub>I(on)</sub>	On-state input voltage	Figure 6	$V_{CE} = 2 V$	I <sub>C</sub> = 250 mA			2.9	V
				I <sub>C</sub> = 300 mA			3	
			$I_I = 250 \mu A$ ,	I <sub>C</sub> = 100 mA		0.9	1.2	
V <sub>CE(sat)</sub>	Collector-emitter saturation voltage	Figure 5	$I_{I} = 350 \ \mu A,$	$I_C = 200 \text{ mA}$		1	1.4	V
			$I_1 = 500 \mu A$ ,	I <sub>C</sub> = 350 mA		1.2	1.7	
I <sub>CEX</sub>	Collector cutoff current	Figure 1	V <sub>CE</sub> = 50 V,	I <sub>1</sub> = 0			100	μΑ
V <sub>F</sub>	Clamp forward voltage	Figure 8	I <sub>F</sub> = 350 mA			1.7	2.2	V
I <sub>I(off)</sub>	Off-state input current	Figure 3	V <sub>CE</sub> = 50 V,	I <sub>C</sub> = 500 μA	30	65		μΑ
I	Input current	Figure 4	V <sub>I</sub> = 3.85 V			0.93	1.35	mA
I <sub>R</sub>	Clamp reverse current	Figure 7	V <sub>R</sub> = 50 V				100	μΑ
Ci	Input capacitance		$V_I = 0$ ,	f = 1 MHz		15	25	pF

# **ELECTRICAL CHARACTERISTICS**

over recommended operating conditions (unless otherwise noted)

	DADAMETED	TEST	TEOT OF	TEST CONDITIONS		Q2003	Α	UL	.Q2004 <i>A</i>	A	
	PARAMETER	FIGURE	TEST CC			TYP	MAX	MIN	TYP	MAX	UNIT
				I <sub>C</sub> = 125 mA						5	
				I <sub>C</sub> = 200 mA			2.7			6	
	On atota langut colling	F:	.,	I <sub>C</sub> = 250 mA			2.9				.,
$V_{I(on)}$	On-state input voltage	Figure 6	V <sub>CE</sub> = 2 V	I <sub>C</sub> = 275 mA						7	V
				I <sub>C</sub> = 300 mA			3				
				I <sub>C</sub> = 350 mA						8	
			$I_1 = 250 \ \mu A$ ,	$I_C = 100 \text{ mA}$		0.9	1.2		0.9	1.1	
$V_{\text{CE(sat)}}$	Collector-emitter saturation voltage	Figure 5	$I_1 = 350 \ \mu A$ ,	$I_C = 200 \text{ mA}$		1	1.4		1	1.3	V
	oataration voltage		$I_I = 500 \ \mu A$ ,	I <sub>C</sub> = 350 mA		1.2	1.7		1.2	1.6	
		Figure 1	$V_{CE} = 50 \text{ V},$	$I_1 = 0$			100			50	
$I_{CEX}$	Collector cutoff current	Figure 2	$V_{CE} = 50 \text{ V},$	$I_1 = 0$						100	μA
		Figure 2	$T_A = 70^{\circ}C$	V <sub>I</sub> = 6 V						500	
$V_{F}$	Clamp forward voltage	Figure 8	$I_F = 350 \text{ mA}$			1.7	2.3		1.7	2	V
$\mathbf{I}_{I(off)}$	Off-state input current	Figure 3	V <sub>CE</sub> = 50 V, T <sub>A</sub> = 70°C,	I <sub>C</sub> = 500 μA		65		50	65		μA
			$V_{I} = 3.85 \text{ V}$			0.93	1.35				
II	Input current	Figure 4	$V_I = 5 V$						0.35	0.5	mA
			V <sub>I</sub> = 12 V						1	1.45	
	Clamp roverse current	Figure 7	V - <b>5</b> 0 V	$T_A = 25^{\circ}C$			100			50	
I <sub>R</sub>	Clamp reverse current Figure 7 $V_R = 50 \text{ V}$	V <sub>R</sub> = 50 V				100			100	μA	
C <sub>i</sub>	Input capacitance		$V_{I} = 0,$	f = 1 MHz		15	25		15	25	pF

Submit Documentation Feedback



## **SWITCHING CHARACTERISTICS**

 $T_A = 25^{\circ}C$ 

PARAMETER		TEST CONDITIONS	ULN2002A ULN	UNIT		
			MIN	TYP	MAX	
t <sub>PLH</sub>	Propagation delay time, low- to high-level output	See Figure 9		0.25	1	μs
$t_{\text{PHL}}$	Propagation delay time, high- to low-level output	See Figure 9		0.25	1	μs
$V_{OH}$	High-level output voltage after switching	$V_S = 50 \text{ V}, I_O = 300 \text{ mA}, \text{ See Figure 10}$	V <sub>S</sub> - 20			mV

## **SWITCHING CHARACTERISTICS**

 $T_A = 25^{\circ}C$ 

PARAMETER		TEST CONDITIONS	ULN		UNIT		
	PARAMETER	TEST CONDITIONS	MIN TYP		MAX	ONII	
t <sub>PLH</sub>	Propagation delay time, low- to high-level output	See Figure 9		0.25	1	μs	
t <sub>PHL</sub>	Propagation delay time, high- to low-level output	See Figure 9		0.25	1	μs	
V <sub>OH</sub>	High-level output voltage after switching	$V_S = 50 \text{ V}, I_O \approx 300 \text{ mA}, \text{ See Figure 10}$	V <sub>S</sub> - 20			mV	

## **SWITCHING CHARACTERISTICS**

 $T_A = -40$ °C to 105°C

PARAMETER		TEST CONDITIONS	ULN		UNIT		
	PARAMETER	TEST CONDITIONS	MIN TYP MA		MAX	UNII	
t <sub>PLH</sub>	Propagation delay time, low- to high-level output	See Figure 9		1	10	μs	
t <sub>PHL</sub>	Propagation delay time, high- to low-level output	See Figure 9		1	10	μs	
$V_{OH}$	High-level output voltage after switching	$V_S = 50 \text{ V}, I_O \approx 300 \text{ mA}, \text{ See Figure 10}$	V <sub>S</sub> -50			mV	

#### **SWITCHING CHARACTERISTICS**

over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST COMPITIONS	ULQ2003/	UNIT		
	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low- to high-level output	See Figure 9		1	10	μs
t <sub>PHL</sub>	Propagation delay time, high- to low-level output	See Figure 9		1	10	μs
$V_{OH}$	High-level output voltage after switching	$V_S = 50 \text{ V}, I_O = 300 \text{ mA}, \text{ See Figure 10}$	V <sub>S</sub> - 20			mV



#### PARAMETER MEASUREMENT INFORMATION

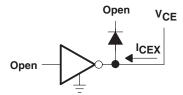


Figure 1. I<sub>CEX</sub> Test Circuit

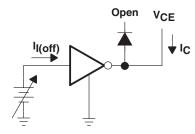


Figure 3. I<sub>I(off)</sub> Test Circuit

A.  $I_I$  is fixed for measuring  $V_{CE(sat)}$ , variable for measuring  $h_{FE}$ .

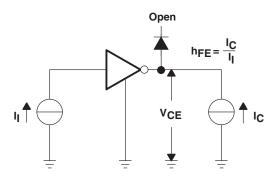


Figure 5. h<sub>FE</sub>, V<sub>CE(sat)</sub> Test Circuit

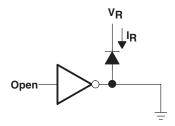


Figure 7. I<sub>R</sub> Test Circuit

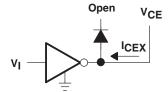


Figure 2. I<sub>CEX</sub> Test Circuit

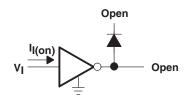


Figure 4. I<sub>I</sub> Test Circuit

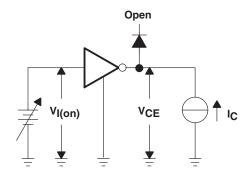


Figure 6. V<sub>I(on)</sub> Test Circuit

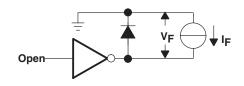


Figure 8. V<sub>F</sub> Test Circuit



# PARAMETER MEASUREMENT INFORMATION (continued)

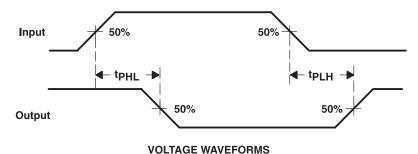
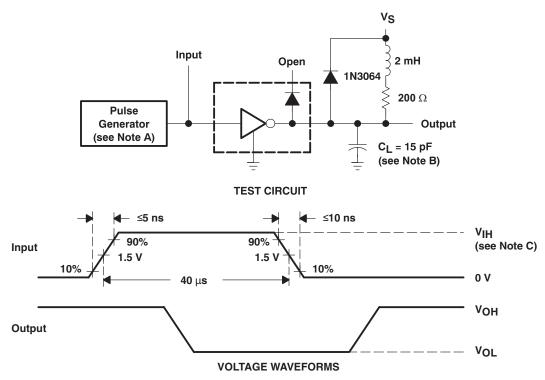


Figure 9. Propagation Delay-Time Waveforms

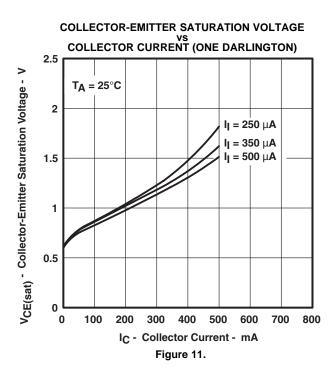


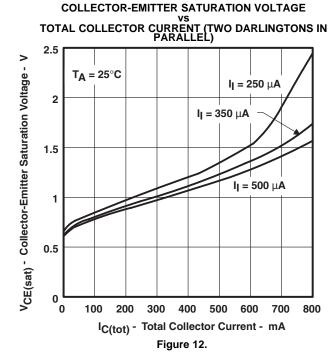
- A. The pulse generator has the following characteristics: PRR = 12.5 kHz,  $Z_0$  = 50  $\Omega$ .
- B. C<sub>L</sub> includes probe and jig capacitance.
- C. For testing the ULN2003A, ULN2003AI, and ULQ2003A,  $V_{IH}$  = 3 V; for the ULN2002A,  $V_{IH}$  = 13 V; for the ULN2004A and the ULQ2004A,  $V_{IH}$  = 8 V.

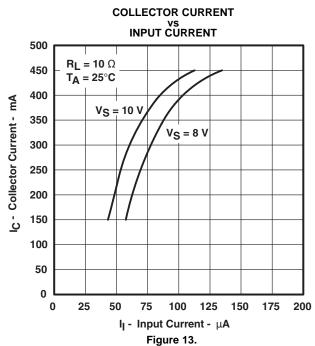
Figure 10. Latch-Up Test Circuit and Voltage Waveforms

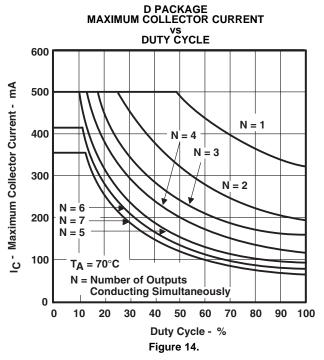


#### TYPICAL CHARACTERISTICS



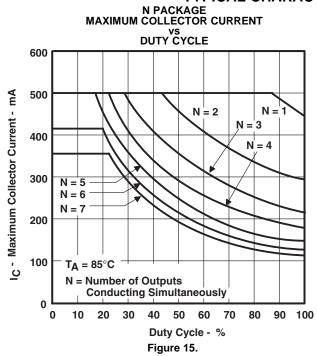


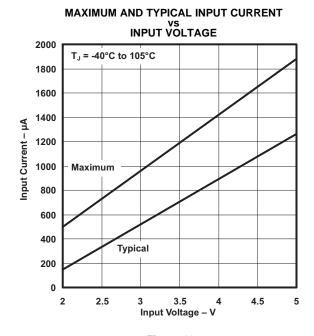


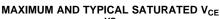




# TYPICAL CHARACTERISTICS (continued)







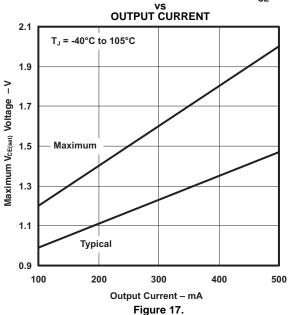
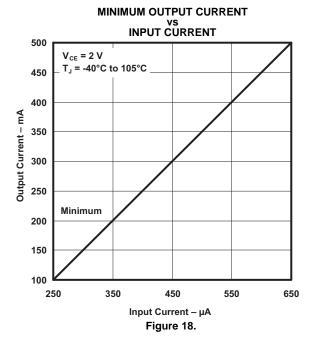


Figure 16.





# **APPLICATION INFORMATION**

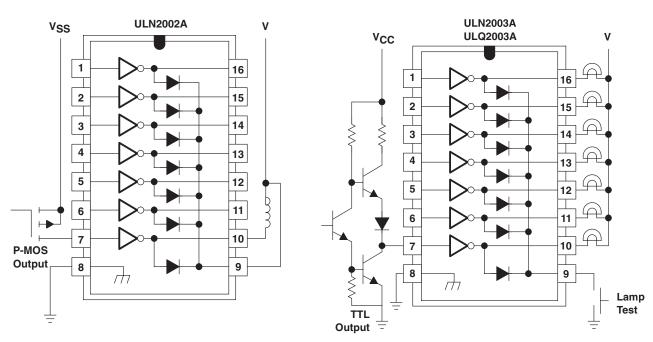


Figure 19. P-MOS to Load

Figure 20. TTL to Load

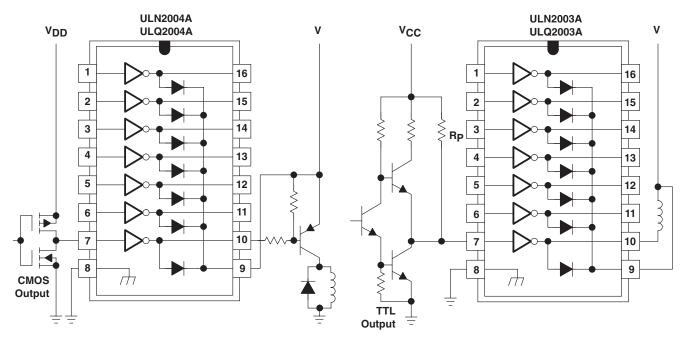
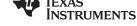


Figure 21. Buffer for Higher Current Loads

Figure 22. Use of Pullup Resistors to Increase Drive Current





SLRS027M - DECEMBER 1976 - REVISED FEBRUARY 2013

# **REVISION HISTORY**

Changes from Revision K (August 2011) to Revision L	Page
Removed reference to obsolete ULN2001 part	1
Changes from Revision L (March 2012) to Revision M	Page
Updated temperature rating for ULN2003AI in the ORDERING INFORMATION table	2

Submit Documentation Feedback





13-Apr-2014

# **PACKAGING INFORMATION**

Orderable Device	Status	Package Type		Pins		Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
ULN2001AD	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI			
ULN2001ADR	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI Call TI			
ULN2001AN	OBSOLETE	PDIP	N	16		TBD	Call TI	Call TI			
ULN2002AD	OBSOLETE	SOIC	D	16		TBD	Call TI	Call TI			
ULN2002AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	NIPDAU N / A for Pkg Type		ULN2002AN	Samples
ULN2002ANE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-20 to 70	ULN2002AN	Samples
ULN2003AD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samples
ULN2003ADE4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samples
ULN2003ADG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samples
ULN2003ADR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samples
ULN2003ADRE4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samples
ULN2003ADRG3	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samples
ULN2003ADRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samples
ULN2003AID	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	ULN2003AI	Samples
ULN2003AIDE4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	ULN2003AI	Samples
ULN2003AIDG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	ULN2003AI	Samples
ULN2003AIDR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 105	ULN2003AI	Samples
ULN2003AIDRE4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	ULN2003AI	Samples
ULN2003AIDRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	ULN2003AI	Samples



13-Apr-2014

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Sample
ULN2003AIN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 105	ULN2003AIN	Sampl
ULN2003AINE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 105	ULN2003AIN	Sampl
ULN2003AINSR	ACTIVE	so	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	ULN2003AI	Sampl
ULN2003AIPW	ACTIVE	TSSOP	P PW 16 90 Green (RoHS CU NIPDAU Level-1-260C-UNLIM -4 & no Sb/Br)		-40 to 105	UN2003AI	Sampl				
ULN2003AIPWE4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	UN2003AI	Sampl
ULN2003AIPWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	UN2003AI	Samp
ULN2003AIPWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 105	UN2003AI	Samp
ULN2003AIPWRE4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	UN2003AI	Samp
ULN2003AIPWRG4	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 105	UN2003AI	Samp
ULN2003AJ	OBSOLETE	CDIP	J	16		TBD	Call TI	Call TI	-55 to 125		
ULN2003AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU   CU SN	N / A for Pkg Type	-20 to 70	ULN2003AN	Samp
ULN2003ANE3	PREVIEW	PDIP	N	16	25	TBD	Call TI	Call TI	-20 to 70		
ULN2003ANE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-20 to 70	ULN2003AN	Samp
ULN2003ANSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samp
ULN2003ANSRE4	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samp
ULN2003ANSRG4	ACTIVE	so	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2003A	Samp
ULN2003APW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	DAU Level-1-260C-UNLIM		UN2003A	Samp
ULN2003APWE4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	UN2003A	Samp
ULN2003APWG4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	UN2003A	Samp



13-Apr-2014

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
ULN2003APWR	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-20 to 70	UN2003A	Samples
ULN2003APWRE4	APWRE4 ACTIVE TSSOP PW 16 2000 Green (RoHS C & no Sb/Br)		CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	UN2003A	Samples				
ULN2003APWRG4	ACTIVE	CTIVE TSSOP PW 16 2000 Green (RoHS CU NIPDAU Level-1-260C-UNLIM & no Sb/Br)		-20 to 70	UN2003A	Sample					
ULN2004AD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Sample
ULN2004ADE4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Samples
ULN2004ADG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Sample
ULN2004ADR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Sample
ULN2004ADRE4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Sample
ULN2004ADRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Sample
ULN2004AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-20 to 70	ULN2004AN	Samples
ULN2004ANE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-20 to 70	ULN2004AN	Samples
ULN2004ANSR	ACTIVE	so	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Sample
ULN2004ANSRG4	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-20 to 70	ULN2004A	Sample
ULQ2003AD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	ULQ2003A	Sample
ULQ2003ADG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		ULQ2003A	Sample
ULQ2003ADR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	ULQ2003A	Sample
ULQ2003ADRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		ULQ2003A	Sample
ULQ2003AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	ULQ2003A	Sample



# PACKAGE OPTION ADDENDUM

13-Apr-2014

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
ULQ2004AD	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	ULQ2004A	Samples
ULQ2004ADG4	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		ULQ2004A	Samples
ULQ2004ADR	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 85	ULQ2004A	Samples
ULQ2004ADRG4	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM		ULQ2004A	Samples
ULQ2004AN	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-40 to 85	ULQ2004AN	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



# **PACKAGE OPTION ADDENDUM**

13-Apr-2014

**Important Information and Disclaimer:** The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

#### OTHER QUALIFIED VERSIONS OF ULQ2003A, ULQ2004A:

Automotive: ULQ2003A-Q1, ULQ2004A-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

# PACKAGE MATERIALS INFORMATION

www.ti.com 31-Jan-2014

# TAPE AND REEL INFORMATION



# TAPE DIMENSIONS + K0 - P1 - B0 W Cavity - A0 -

	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

# QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



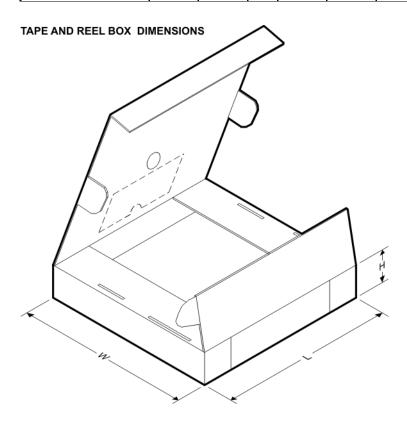
#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ULN2003ADR	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
ULN2003ADR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULN2003ADRG3	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
ULN2003ADRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULN2003AIDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULN2003AIDR	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
ULN2003AIDRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULN2003AIPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
ULN2003AIPWR	TSSOP	PW	16	2000	330.0	12.4	7.0	5.6	1.6	8.0	12.0	Q1
ULN2003AIPWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
ULN2003APWR	TSSOP	PW	16	2000	330.0	12.4	7.0	5.6	1.6	8.0	12.0	Q1
ULN2003APWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
ULN2003APWRG4	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
ULN2004ADR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULN2004ADR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULN2004ADR	SOIC	D	16	2500	330.0	16.8	6.5	10.3	2.1	8.0	16.0	Q1
ULN2004ADRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULN2004ADRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1

# **PACKAGE MATERIALS INFORMATION**

www.ti.com 31-Jan-2014

Device	_	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ULQ2003ADR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
ULQ2003ADRG4	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ULN2003ADR	SOIC	D	16	2500	364.0	364.0	27.0
ULN2003ADR	SOIC	D	16	2500	333.2	345.9	28.6
ULN2003ADRG3	SOIC	D	16	2500	364.0	364.0	27.0
ULN2003ADRG4	SOIC	D	16	2500	333.2	345.9	28.6
ULN2003AIDR	SOIC	D	16	2500	333.2	345.9	28.6
ULN2003AIDR	SOIC	D	16	2500	364.0	364.0	27.0
ULN2003AIDRG4	SOIC	D	16	2500	333.2	345.9	28.6
ULN2003AIPWR	TSSOP	PW	16	2000	367.0	367.0	35.0
ULN2003AIPWR	TSSOP	PW	16	2000	364.0	364.0	27.0
ULN2003AIPWRG4	TSSOP	PW	16	2000	367.0	367.0	35.0
ULN2003APWR	TSSOP	PW	16	2000	364.0	364.0	27.0
ULN2003APWR	TSSOP	PW	16	2000	367.0	367.0	35.0
ULN2003APWRG4	TSSOP	PW	16	2000	367.0	367.0	35.0
ULN2004ADR	SOIC	D	16	2500	367.0	367.0	38.0
ULN2004ADR	SOIC	D	16	2500	333.2	345.9	28.6



# **PACKAGE MATERIALS INFORMATION**

www.ti.com 31-Jan-2014

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ULN2004ADR	SOIC	D	16	2500	364.0	364.0	27.0
ULN2004ADRG4	SOIC	D	16	2500	333.2	345.9	28.6
ULN2004ADRG4	SOIC	D	16	2500	367.0	367.0	38.0
ULQ2003ADR	SOIC	D	16	2500	333.2	345.9	28.6
ULQ2003ADRG4	SOIC	D	16	2500	367.0	367.0	38.0

## 14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

# N (R-PDIP-T\*\*)

# PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



# D (R-PDS0-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



# D (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



# PW (R-PDSO-G16)

# PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



# **MECHANICAL DATA**

# NS (R-PDSO-G\*\*)

# 14-PINS SHOWN

# PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



#### IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have not been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

#### **Products Applications**

power.ti.com

Audio www.ti.com/audio Automotive and Transportation www.ti.com/automotive Communications and Telecom Amplifiers amplifier.ti.com www.ti.com/communications **Data Converters** dataconverter.ti.com Computers and Peripherals www.ti.com/computers **DLP® Products** www.dlp.com Consumer Electronics www.ti.com/consumer-apps

DSP **Energy and Lighting** dsp.ti.com www.ti.com/energy Clocks and Timers www.ti.com/clocks Industrial www.ti.com/industrial Interface interface.ti.com Medical www.ti.com/medical logic.ti.com Logic Security www.ti.com/security Space, Avionics and Defense www.ti.com/space-avionics-defense

Microcontrollers microcontroller.ti.com Video and Imaging www.ti.com/video

RFID www.ti-rfid.com

Power Mgmt

**OMAP Applications Processors** www.ti.com/omap **TI E2E Community** e2e.ti.com

Wireless Connectivity www.ti.com/wirelessconnectivity